Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	564
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	140
Number of Gates	4000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	176-LQFP
Supplier Device Package	176-TQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1440a-tqg176i

Product Plan

Device/Package	Speed Grade[1]				Application[1]			
	Std.	–1	–2	–3	C	I	M	B
A1415A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	✓	–
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	✓	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	✓	–
100-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	–	–
A14V15A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
A1425A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓		
100-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	–	–
132-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
133-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	D	D
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
A14V25A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A1440A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	✓	D	D	✓	✓	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	✓	D	D	✓	✓	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
175-Pin Ceramic Pin Grid Array (CPGA)	D	D	D	D	D	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–

Notes:

1. *Applications:*
   C = Commercial
   I = Industrial
   M = Military
2. *Commercial only*

Availability:
✓ = Available
P = Planned
– = Not planned
D = Discontinued

Speed Grade:
–1 = Approx. 15% faster than Std.
–2 = Approx. 25% faster than Std.
–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

Horizontal Routing

Horizontal channels are located between the rows of modules and are composed of several routing tracks. The horizontal routing tracks within the channel are divided into one or more segments. The minimum horizontal segment length is the width of a module-pair, and the maximum horizontal segment length is the full length of the channel. Any segment that spans more than one-third the row length is considered a long horizontal segment. A typical channel is shown in Figure 2-7. Undedicated horizontal routing tracks are used to route signal nets. Dedicated routing tracks are used for the global clock networks and for power and ground tie-off tracks.

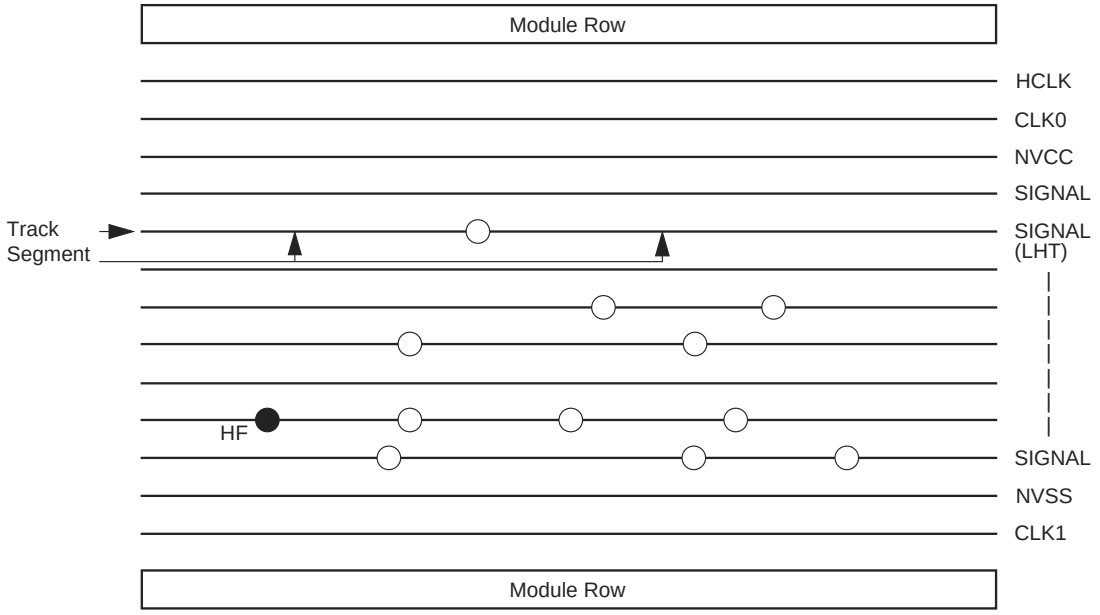


Figure 2-7 • **Horizontal Routing Tracks and Segments**

Vertical Routing

Other tracks run vertically through the modules. Vertical tracks are of three types: input, output, and long. Vertical tracks are also divided into one or more segments. Each segment in an input track is dedicated to the input of a particular module. Each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing. Each output segment spans four channels (two above and two below), except near the top and bottom of the array where edge effects occur. LVTs contain either one or two segments. An example of vertical routing tracks and segments is shown in Figure 2-8.

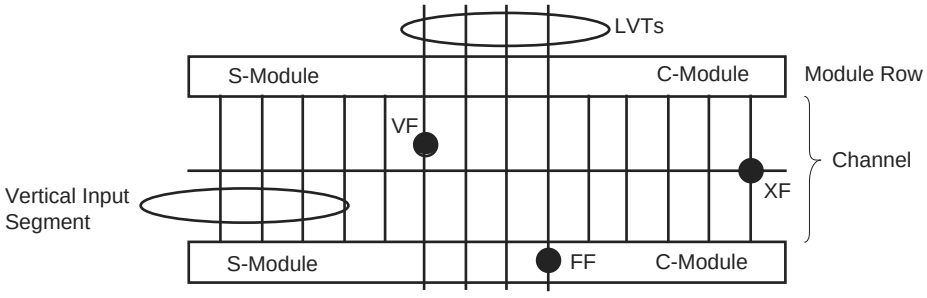


Figure 2-8 • **Vertical Routing Tracks and Segments**

Antifuse Connections

An antifuse is a “normally open” structure as opposed to the normally closed fuse structure used in PROMs or PALs. The use of antifuses to implement a programmable logic device results in highly testable structures as well as an efficient programming architecture. The structure is highly testable because there are no preexisting connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed as well as isolate individual circuit structures to be tested. This can be done both before and after programming. For example, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Four types of antifuse connections are used in the routing structure of the ACT 3 array. (The physical structure of the antifuse is identical in each case; only the usage differs.)

Table 2-1 shows four types of antifuses.

Table 2-1 • **Antifuse Types**

Type	Description
XF	Horizontal-to-vertical connection
HF	Horizontal-to-horizontal connection
VF	Vertical-to-vertical connection
FF	"Fast" vertical connection

Examples of all four types of connections are shown in Figure 2-7 on page 2-6 and Figure 2-8 on page 2-6.

Module Interface

Connections to Logic and I/O modules are made through vertical segments that connect to the module inputs and outputs. These vertical segments lie on vertical tracks that span the entire height of the array.

Module Input Connections

The tracks dedicated to module inputs are segmented by pass transistors in each module row. During normal user operation, the pass transistors are inactive, which isolates the inputs of a module from the inputs of the module directly above or below it. During certain test modes, the pass transistors are active to verify the continuity of the metal tracks. Vertical input segments span only the channel above or the channel below. The logic modules are arranged such that half of the inputs are connected to the channel above and half of the inputs to segments in the channel below, as shown in Figure 2-9.

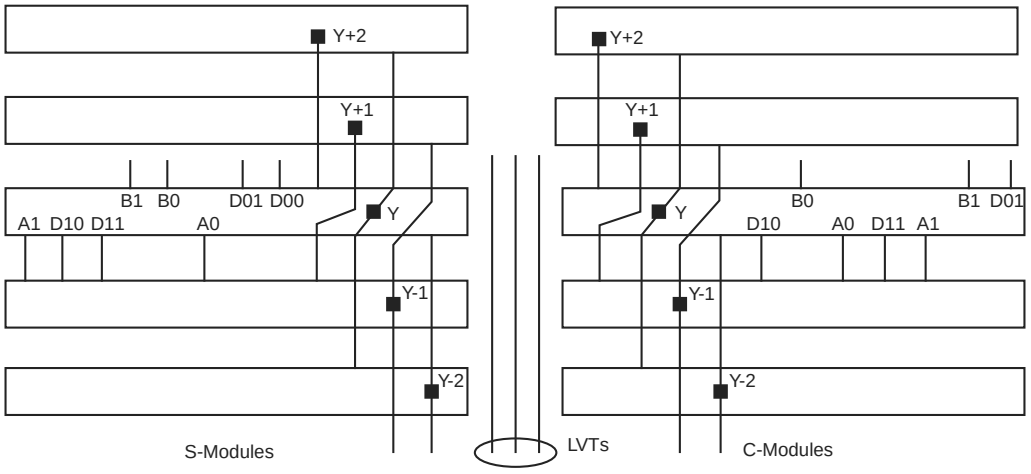


Figure 2-9 • **Logic Module Routing Interface**

5 V Operating Conditions

Table 2-2 • **Absolute Maximum Ratings[1], Free Air Temperature Range**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current[2]	±20	mA
T_{STG}	Storage temperature	–65 to +150	°C

Notes:

1. *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.*
2. *Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.*

Table 2-3 • **Recommended Operating Conditions**

Parameter	Commercial	Industrial	Military	Units
Temperature range*	0 to +70	–40 to +85	–55 to +125	°C
5 V power supply tolerance	±5	±10	±10	%VCC

*Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.*

Table 2-4 • **Electrical Specifications**

			Commercial		Industrial		Military		
Symbol	Parameter	Test Condition	Min.	Max.	Min.	Max.	Min.	Max.	Units
VOH[1,2]	High level output	IOH = –4 mA (CMOS)	–	–	3.7	–	3.7	–	V
		IOH = –6 mA (CMOS)	3.84						V
		IOH = –10 mA (TTL)[3]	2.40						V
VOL[1,2]	Low level output	IOL = +6 mA (CMOS)		0.33		0.4		0.4	V
		IOL = +12 mA (TTL)[3]		0.50					
VIH	High level input	TTL inputs	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIL	Low level input	TTL inputs	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
IIN	Input leakage	VI = VCC or GND	–10	+10	–10	+10	–10	+10	µA
IOZ	3-state output leakage	VO = VCC or GND	–10	+10	–10	+10	–10	+10	µA
C_{IO}	I/O capacitance[3,4]			10		10		10	pF
ICC(S)	Standby VCC supply current (typical = 0.7 mA)			2		10		20	mA
ICC(D)	Dynamic VCC supply current. See the Power Dissipation section.								

Notes:

1. *Microsemi devices can drive and receive either CMOS or TTL signal levels. No assignment of I/Os as TTL or CMOS is required.*
2. *Tested one output at a time, VCC = minimum.*
3. *Not tested; for information only.*
4. *VOUT = 0 V, f = 1 MHz*
5. *Typical standby current = 0.7 mA. All outputs unloaded. All inputs = VCC or GND.*

Power Dissipation

P = [ICC standby + Iactive] * VCC * IOL * VOL * N + IOH* (VCC – VOH) * M

EQ 3

where:

ICC standby is the current flowing when no inputs or outputs are changing

Iactive is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source current.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M equals the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the design and on the system I/O. The power can be divided into two components: static and active.

Static Power Component

Microsemi FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated in Table 2-9 for commercial, worst case conditions.

Table 2-9 • **Standby Power Calculation**

ICC	VCC	Power
2 mA	5.25 V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

Active Power Component

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces and load device inputs.

An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by EQ 4.

Power (µW) = C_{EQ} * VCC^2 * F

EQ 4

Where:

C_{EQ} is the equivalent capacitance expressed in pF.

VCC is the power supply in volts.

F is the switching frequency in MHz.

***Table 2-11* • Fixed Capacitance Values for Microsemi FPGAs**

Device Type	r1, routed_Clk1	r2, routed_Clk2
A1415A	60	60
A14V15A	57	57
A1425A	75	75
A14V25A	72	72
A1440A	105	105
A14V40A	100	100
A1440B	105	105
A1460A	165	165
A14V60A	157	157
A1460B	165	165
A14100A	195	195
A14V100A	185	185
A14100B	195	195

***Table 2-12* • Fixed Clock Loads (s1/s2)**

Device Type	s1, Clock Loads on Dedicated Array Clock	s2, Clock Loads on Dedicated I/O Clock
A1415A	104	80
A14V15A	104	80
A1425A	160	100
A14V25A	160	100
A1440A	288	140
A14V40A	288	140
A1440B	288	140
A1460A	432	168
A14V60A	432	168
A1460B	432	168
A14100A	697	228
A14V100A	697	228
A14100B	697	228

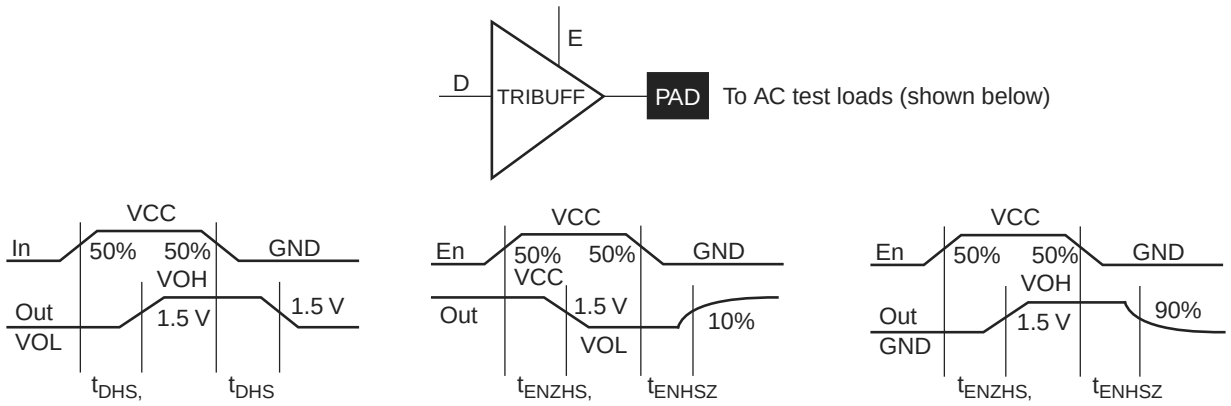


Figure 2-11 • **Output Buffers**

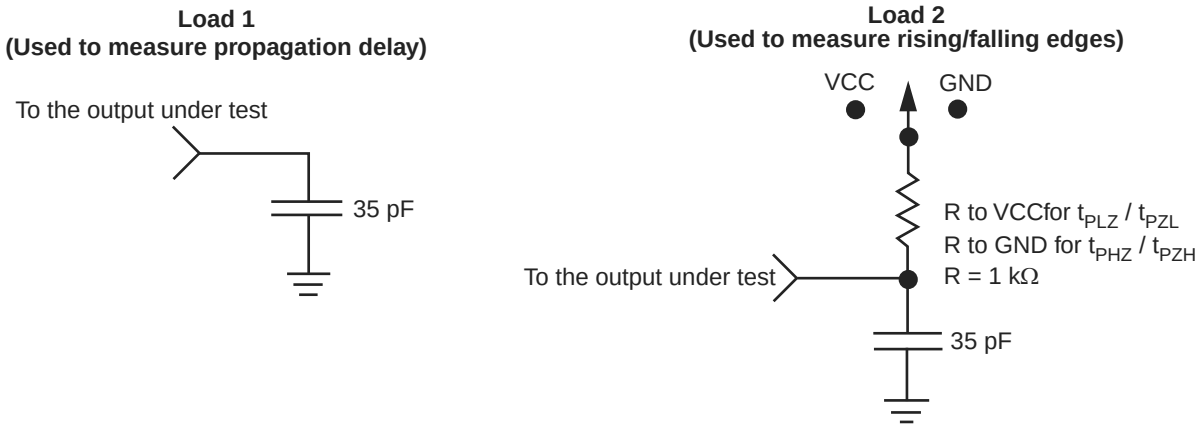


Figure 2-12 • **AC Test Loads**

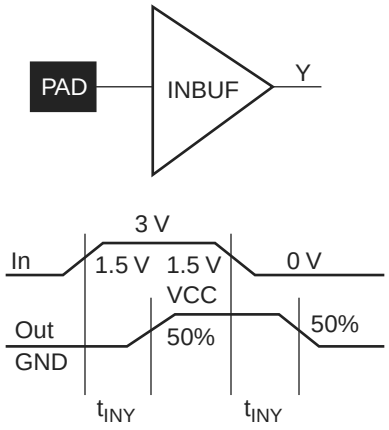


Figure 2-13 • **Input Buffer Delays**

A1425A, A14V25A Timing Characteristics (continued)

Table 2-24 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing[1]		–3 Speed[2]		–2 Speed[2]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		6.5		7.5		8.5		10.0		13.0	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		6.5		7.5		8.5		10.0		13.0	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		7.5		7.5		9.0		10.0		13.0	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		6.7		7.5		8.5		10.0		13.0	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		6.7		7.5		9.0		10.0		13.0	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		8.9		8.9		10.7		11.8		15.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

*Notes: **

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A14100A, A14V100A Timing Characteristics (continued)

Table 2-36 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing[1]		–3 Speed[2]		–2 Speed[2]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.5		9.5		10.5		12.0		15.6	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.0		12.0		15.6	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.4		13.8		17.9	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

*Notes: **

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A14100A, A14V100A Timing Characteristics (continued)

Table 2-37 • **A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

Dedicated (hardwired) I/O Clock Network		–3 Speed[1]		–2 Speed[1]		–1 Speed		Std. Speed		3.3 V Speed[1]		Units
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{IOCKH}	Input Low to High (pad to I/O module input)		2.3		2.6		3.0		3.5		4.5	ns
t_{IOPWH}	Minimum Pulse Width High	2.4		3.3		3.8		4.8		6.5		ns
t_{IPOWL}	Minimum Pulse Width Low	2.4		3.3		3.8		4.8		6.5		ns
t_{IOSAPW}	Minimum Asynchronous Pulse Width	2.4		3.3		3.8		4.8		6.5		ns
t_{IOCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		0.6	ns
t_{IOP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f_{IOMAX}	Maximum Frequency		200		150		125		100		75	MHz
Dedicated (hardwired) Array Clock												
t_{HCKH}	Input Low to High (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t_{HCKL}	Input High to Low (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t_{HPWH}	Minimum Pulse Width High	2.4		3.3		3.8		4.8		6.5		ns
t_{HPWL}	Minimum Pulse Width Low	2.4		3.3		3.8		4.8		6.5		ns
t_{HCKSW}	Delta High to Low, Low Slew		0.6		0.6		0.7		0.8		0.6	ns
t_{HP}	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f_{HMAX}	Maximum Frequency		200		150		125		100		75	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t_{RCKL}	Input High to Low (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t_{RPWH}	Min. Pulse Width High (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t_{RPWL}	Min. Pulse Width Low (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t_{RCKSW}	Maximum Skew (FO = 128)		1.2		1.4		1.6		1.8		1.8	ns
t_{RP}	Minimum Period (FO = 64)	8.3		9.3		11.1		12.5		16.7		ns
f_{RMAX}	Maximum Frequency (FO = 64)		120		105		90		80		60	MHz
Clock-to-Clock Skews												
$t_{IOHCKSW}$	I/O Clock to H-Clock Skew	0.0	2.6	0.0	2.7	0.0	2.9	0.0	3.0	0.0	3.0	ns
$t_{IORCKSW}$	I/O Clock to R-Clock Skew (FO = 64) (FO = 350)	0.0 0.0	1.7 5.0	0.0 0.0	1.7 5.0	0.0 0.0	1.7 5.0	0.0 0.0	1.7 5.0	0.0 0.0	5.0 5.0	ns
t_{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 350)	0.0 0.0	1.3 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	0.0 0.0	1.0 3.0	ns

*Notes: **

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Delays based on 35 pF loading.*

SDO **Serial Data Output (Output)**

Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

DCLK **Diagnostic Clock (Input)**

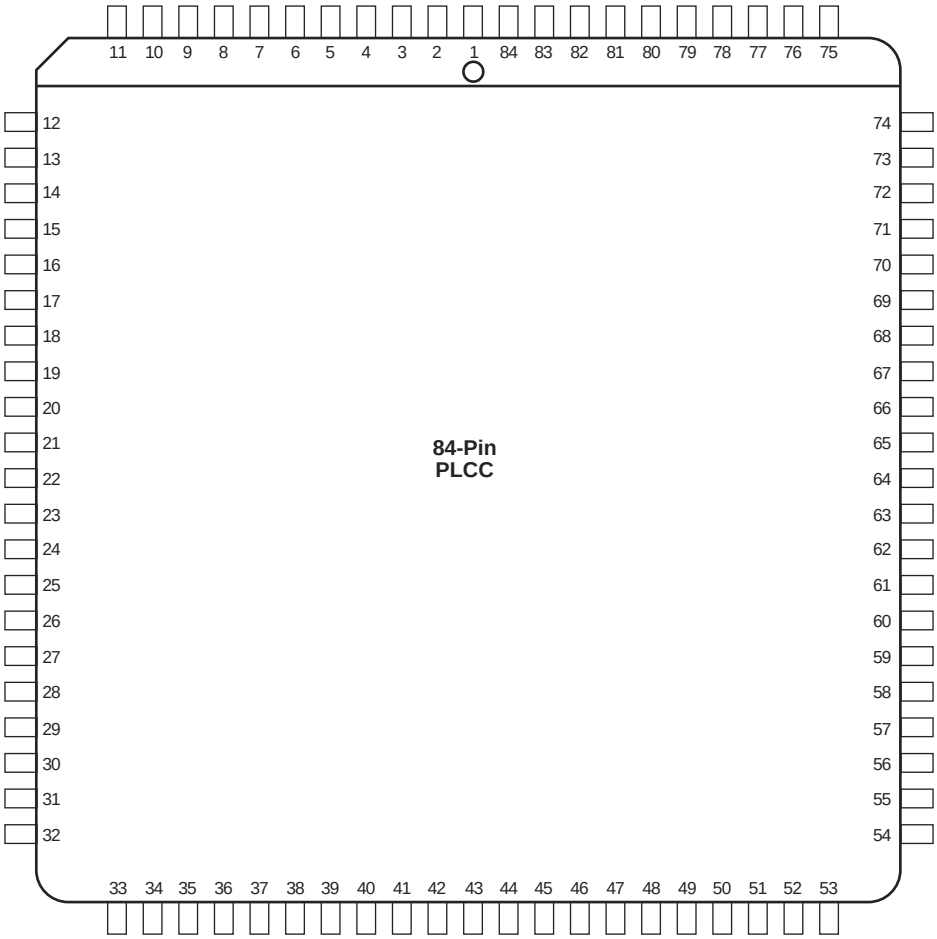
Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

VCC **5 V Supply Voltage**

HIGH supply voltage.

3 – Package Pin Assignments

PL84



Note: This is the top view of the package.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx.

PL84			
Pin Number	**A1415, A14V15 Function**	**A1425, A14V25 Function**	**A1440, A14V40 Function**
1	VCC	VCC	VCC
2	GND	GND	GND
3	VCC	VCC	VCC
4	PRA, I/O	PRA, I/O	PRA, I/O
11	DCLK, I/O	DCLK, I/O	DCLK, I/O
12	SDI, I/O	SDI, I/O	SDI, I/O
16	MODE	MODE	MODE
27	GND	GND	GND
28	VCC	VCC	VCC
40	PRB, I/O	PRB, I/O	PRB, I/O
41	VCC	VCC	VCC
42	GND	GND	GND
43	VCC	VCC	VCC
45	HCLK, I/O	HCLK, I/O	HCLK, I/O
52	SDO	SDO	SDO
53	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
59	VCC	VCC	VCC
60	VCC	VCC	VCC
61	GND	GND	GND
68	VCC	VCC	VCC
69	GND	GND	GND
74	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
83	CLKA, I/O	CLKA, I/O	CLKA, I/O
84	CLKB, I/O	CLKB, I/O	CLKB, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

VQ100			
Pin Number	**A1415, A14V15 Function**	**A1425, A14V25 Function**	**A1440, A14V40 Function**
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
7	MODE	MODE	MODE
8	VCC	VCC	VCC
9	GND	GND	GND
20	VCC	VCC	VCC
21	NC	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	VCC	VCC	VCC
36	GND	GND	GND
37	VCC	VCC	VCC
39	HCLK, I/O	HCLK, I/O	HCLK, I/O
49	SDO	SDO	SDO
50	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
51	GND	GND	GND
57	VCC	VCC	VCC
58	VCC	VCC	VCC
67	VCC	VCC	VCC
68	GND	GND	GND
69	GND	GND	GND
74	NC	I/O	I/O
75	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
87	CLKA, I/O	CLKA, I/O	CLKA, I/O
88	CLKB, I/O	CLKB, I/O	CLKB, I/O
89	VCC	VCC	VCC
90	VCC	VCC	VCC
91	GND	GND	GND
92	PRA, I/O	PRA, I/O	PRA, I/O
93	NC	I/O	I/O
100	DCLK, I/O	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

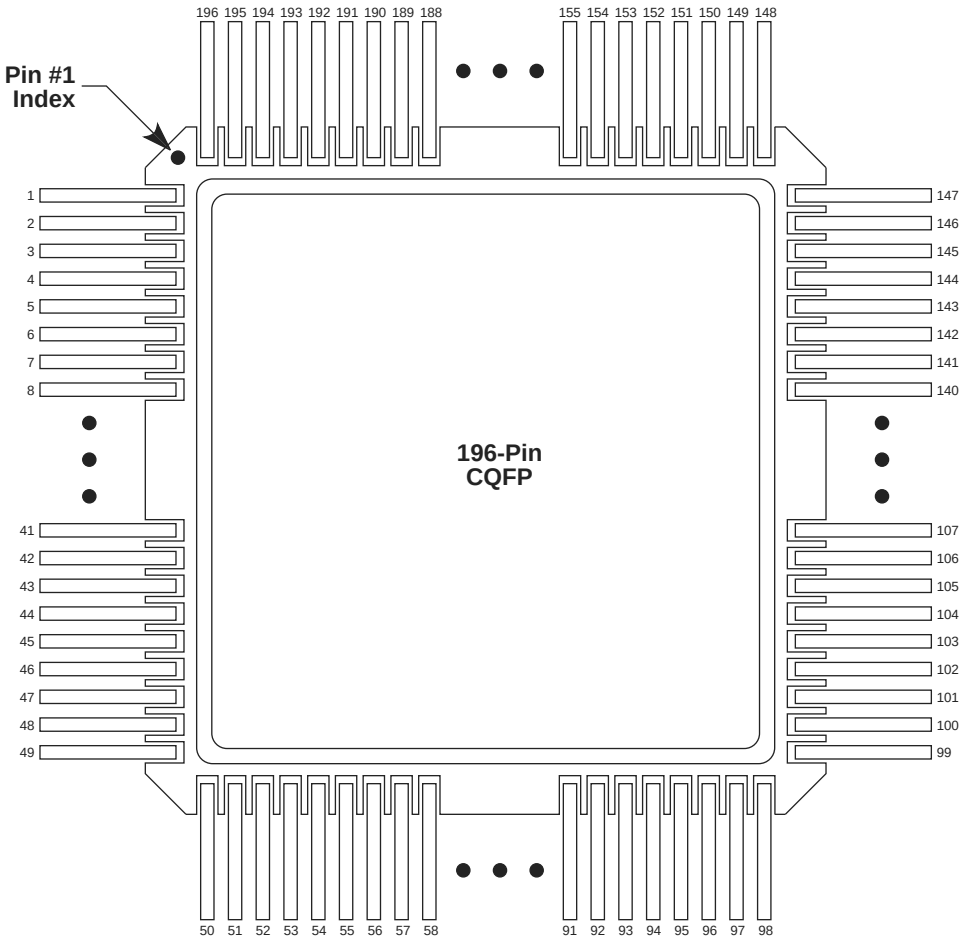
CQ132	
Pin Number	**A1425 Function**
1	NC
2	GND
3	SDI, I/O
9	MODE
10	GND
11	VCC
22	VCC
26	GND
27	VCC
34	NC
36	GND
42	GND
43	VCC
48	PRB, I/O
50	HCLK, I/O
58	GND
59	VCC
63	SDO
64	IOPCL, I/O
65	GND
66	NC

CQ132	
Pin Number	**A1425 Function**
67	NC
74	GND
75	VCC
78	VCC
89	VCC
90	GND
91	VCC
92	GND
98	IOCLK, I/O
99	NC
100	NC
101	GND
106	GND
107	VCC
116	CLKA, I/O
117	CLKB, I/O
118	PRA, I/O
122	GND
123	VCC
131	DCLK, I/O
132	NC

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ196



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

CQ196	
Pin Number	**A1460 Function**
1	GND
2	SDI, I/O
11	MODE
12	VCC
13	GND
37	GND
38	VCC
39	VCC
51	GND
52	GND
59	VCC
64	GND
77	HCLK, I/O
79	PRB, I/O
86	GND
94	VCC
98	GND
99	SDO
100	IOPCL, I/O

CQ196	
Pin Number	**A1460 Function**
101	GND
110	VCC
111	VCC
112	GND
137	VCC
138	GND
139	GND
140	VCC
148	IOCLK, I/O
149	GND
155	VCC
162	GND
172	CLKA, I/O
173	CLKB, I/O
174	PRA, I/O
183	GND
189	VCC
193	GND
196	DCLK, I/O

Notes:

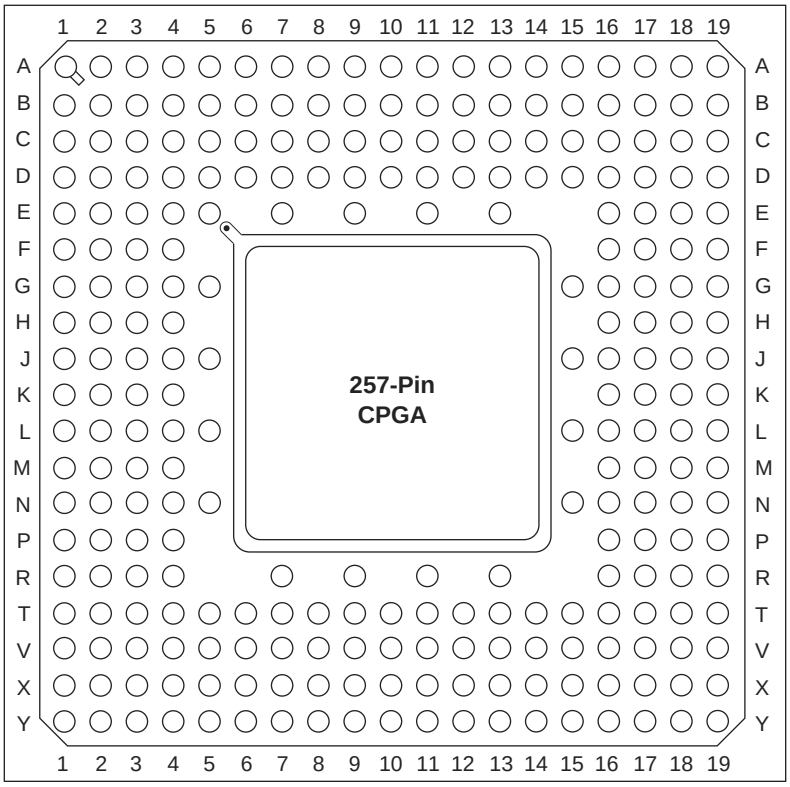
1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG133	
A1425 Function	**Location**
CLKA or I/O	D7
CLKB or I/O	B6
DCLK or I/O	D4
GND	A2, C3, C7, C11, C12, F10, G3, G11, L3, L7, L11, M3, N12
HCLK or I/O	K7
IOCLK or I/O	C10
IOPCL or I/O	L10
MODE	E3
NC	A1, A7, A13, G1, G13, N1, N7, N13
PRA or I/O	A6
PRB or I/O	L6
SDI or I/O	C2
SDO	M11
VCC	B2, B7, B12, E11, G2, G12, J2, J12, M2, M7, M12

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG133 package has been discontinued.

PG257



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

PG257	
A14100 Function	**Location**
CLKA or I/O	L4
CLKB or I/O	L5
DCLK or I/O	E4
GND	B16, C4, D4, D10, D16, E11, J5, K4, K16, L15, R4, T4, T10, T16, T17, X7
HCLK or I/O	J16
IOCLK or I/O	T5
IOPCL or I/O	R16
MODE	A5
NC	E5
PRA or I/O	J1
PRB or I/O	J17
SDI or I/O	B4
SDO	R17
VCC	C3, C10, C13, C17, K3, K17, V3, V7, V10, V17, X14

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.